

# iFit : a simple generic data analysis framework

Example use with full Reitveld analysis using  
virtual experiments.

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## History and development

**First release** August 2011, but designed 2 prototypes since 2003.  
 Actively developed since 2009.

**Development team:** me  
 Beta-testers and friendly users: *P. Willendrup, L. Udby, H. Jacobsen.*

**Licence:** EUPL. ILL software.

**Funding:** none (~10% of my time).

**Project size:** Core is about 25 kLOC. Total 55 kLOC with docs and contrib.  
 Code is 3 Mb size only + doc and example data files.

**Stability:** good (most features are implemented and functional).

**Rationale:** one object to hold data sets, one to hold models, and methods to handle both (load, save, pure math, fitting, plot, ...)

**Built with Matlab:** distributed as well as standalone executable (no need for Matlab license, for *Linux, MacOSX, Windows*). Debian packages.

## What can iFit do for you

- ◆ Handle data sets typically up to a few Gb.
- ◆ Import/export any text-based and a variety of binary data file (*load/save*)  
including NeXus/HDF, EDF, CBF/imgCIF, SPE, McStas, event files...
- ◆ Display data sets (*plot*) in 1D, 2D, 3D
- ◆ Apply mathematical operators (50+) directly on data sets (+-/\*, ...).
- ◆ Carry signal, axes, error bars, ... along operations
- ◆ Record data sets history along operations
- ◆ Optimize any multi-parameter problem (*fmin*).
- ◆ Fit model function onto data sets (*fits*).

iFit consists in the following parts :

### **iData**

to store **data sets** (e.g. files), display and manipulate them.  
Any dimensionality/size

### **iFunc**

to store **models** (e.g. fit functions), display and fit to data sets.  
Symbolic evaluation, any dimensionality

Libraries for Loaders, Optimisation and pre-defined Models

# Examples

## Get documentation

```
>> doc(iData)
```

## Import data files (37 formats supported)

```
>> a=iData('filename'); b=iData('directory'); c=iData(""); % file selector
```

## Manipulate data sets (and models)

Just like numbers, *e.g.*  $d=a+b$

Resolves axes intersection, rebinning, dimension mismatch .. transparently

List methods with *methods iData* and *methods iFunc*

## Display data sets

```
>> disp(a); plot(a);
```

## Save data sets (29 formats supported)

```
>> save(a, 'filename.ext'); save (iData, 'formats') % lists all supported formats
```

## Fit to a model

```
>> fits(a, gauss); fits(a, gauss+gauss); fits(iData) % get the list of models
>> m=iFunc('expr. p, x,y,z...'); edit(iFunc); % edit/create a new model
>> m=convn(gauss,lorz); plot(m); % a Voigt function
```

# Powder Rietveld refinement basics

Currently, a powder structure is refined from a diffractogram as follows:

- **Import** the raw data.
- **Normalize** detector efficiency with a reference sample (Vanadium).
- **Subtract** empty cell making use of the sample transmission.
- Define an **initial structure** *SpcG abc,  $\alpha\beta\gamma XYZ$ ...*
- Estimate the instrument **resolution** parameters *UVW* from measurement configuration  $\alpha_{1-3}$   $\eta$  and Caglioti equations. These *UVW* parameters are often pre-determined from the instrument calibration.
- For each powder structure parameter set, compute a perfect diffractogram and **convolute** each Bragg peak by a Voigt function of width= $f(\theta, UVW)$  depending on the angle. Vertical divergence adds **asymmetry** and **broadening**. The background level is subtracted for each iteration (e.g. quadratic).
- Minimize the **least-square** criteria using e.g. gradient or simulated annealing optimisers. The whole process is the Rietveld method.

In practice, the background level (not a constant) and peak asymmetry are additional parameters together with the powder structure.



# Powder Rietveld refinement theory

## Integral

$$L \propto L_0 = \frac{\alpha_1 \alpha_2 \alpha_3 \cot \theta_M}{\sqrt{\alpha_1^2 + \alpha_2^2 + 4\beta^2}}$$

## Width

$$H_{\text{Peak}} \propto \frac{L}{A_{1/2}}$$

$$A_{1/2}^2 = U \tan^2 \theta_S + V \tan \theta_S + W$$

$$U = \frac{4(\alpha_1^2 \alpha_2^2 + \alpha_1^2 \beta^2 + \alpha_2^2 \beta^2)}{\tan^2 \theta_M (\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$

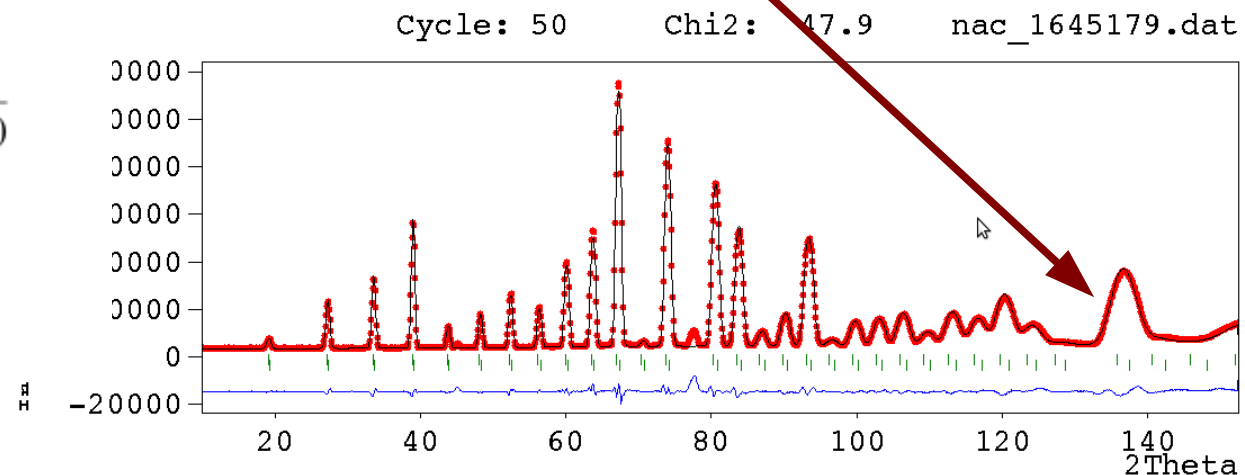
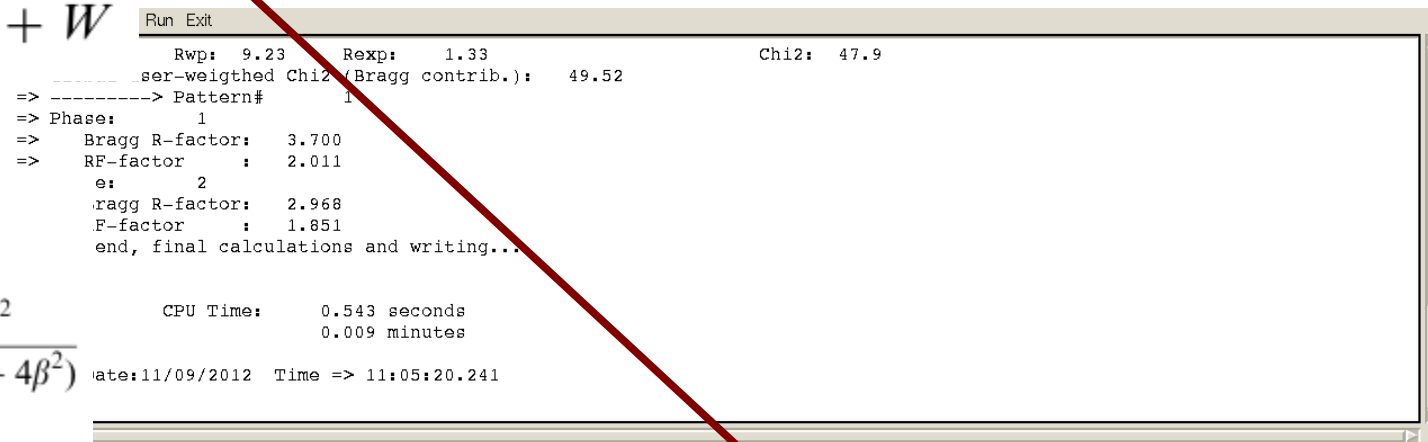
$$= \frac{4}{\tan^2 \theta_M} \left( \frac{1}{\alpha_1^2} + \frac{1}{\alpha_2^2} + \frac{1}{\beta^2} \right) \frac{\alpha_1^2 \alpha_2^2 \beta^2}{(\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$

$$V = \frac{4\alpha_2^2(\alpha_1^2 + 2\beta^2)}{\tan \theta_M (\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$

$$= \frac{4}{\tan \theta_M} \left( \frac{1}{\beta^2} + \frac{2}{\alpha_1^2} \right) \frac{\alpha_1^2 \alpha_2^2 \beta^2}{(\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$

$$W = \alpha_3^2 + \frac{(\alpha_1^2 \alpha_2^2 + 4\beta^2 \alpha_2^2)}{(\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$

$$= \alpha_3^2 + \left( \frac{1}{\beta^2} + \frac{4}{\alpha_1^2} \right) \frac{\alpha_1^2 \alpha_2^2 \beta^2}{(\alpha_1^2 + \alpha_2^2 + 4\beta^2)}$$



G. Caglioti et al, *NIM* **3** (1958) 223

A.W. Hewat, *NIM* **127** (1975) 361

L.D. Cussen, *NIM A* **554** (2005) 406

## Is it possible to reduce the number of parameters to fit and improve the refinement quality/robustness ?

*Yes (I think)*

- ◆ Use **McStas** to model the diffractometer, including container, ...  
*No more UVW, no explicit analytical approximation.*
- ◆ Use the *PowderN* (McStas sample) to model the diffraction from the powder. Requires a reflection list.
- ◆ Use **CrysFML** (FullProf) routines to relate the powder structure parameters to the reflection list needed by *PowderN*
- ◆ Use **iFit** to transparently import both measurement and simulated data sets, compare them (least-squares) and optimise parameters.

*Let's try that ...*

*Resources: 2 ½ months student placement this summer*

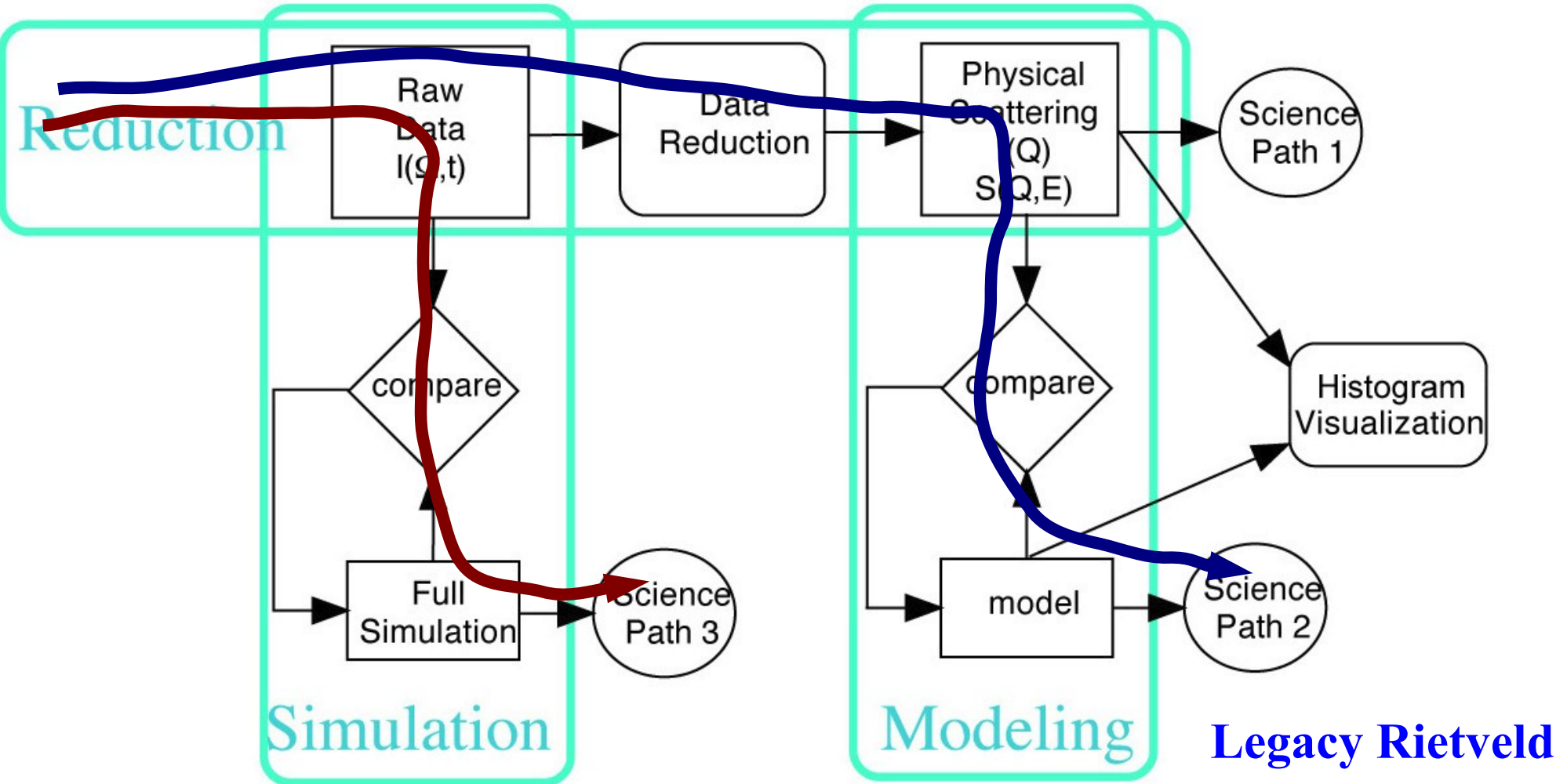
*Student: Marta Bolsa-Ferruz*



# Legacy Reduction-Analysis vs. Full simulation

We have used iFit to test a full simulation data analysis procedure for powders.

**D20 raw data**



**McStas with CrysFML calls**  
**Optimisation with iFit (used swarm here)**  
**Least-Square criteria**

# Diffraction virtual experiment

We set-up a full simulation of a power sample in a D20 model.

## D20 thermal diffractometer:

17 m from the ILL RHF reactor

$\lambda = 2.41 \text{ \AA}$ , Cu002, take-of  $42^\circ$

No collimation  $\alpha_{1-3}$

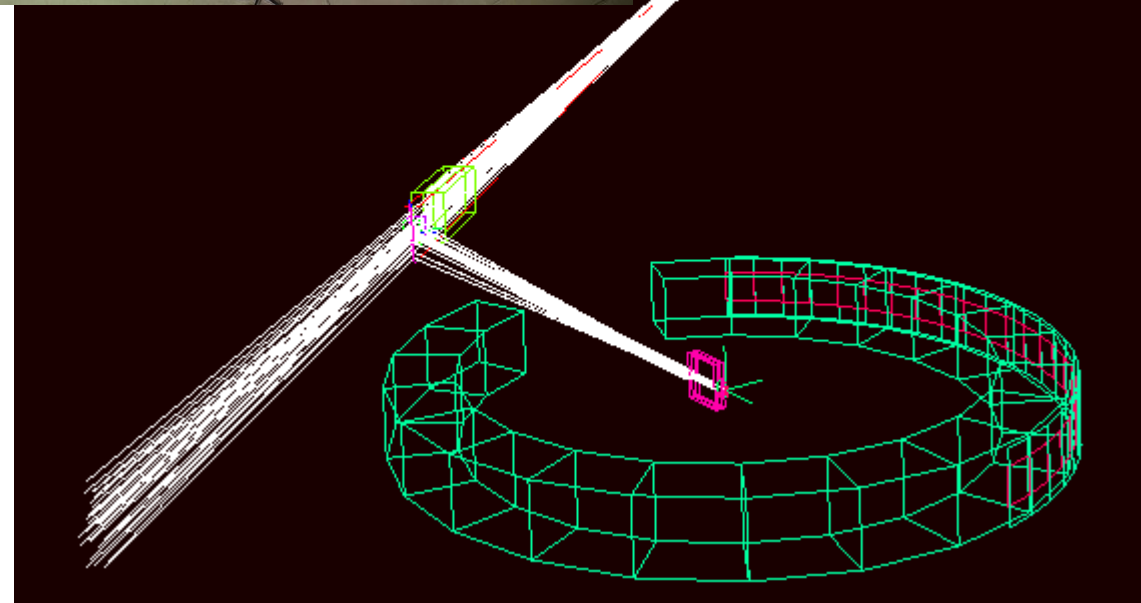
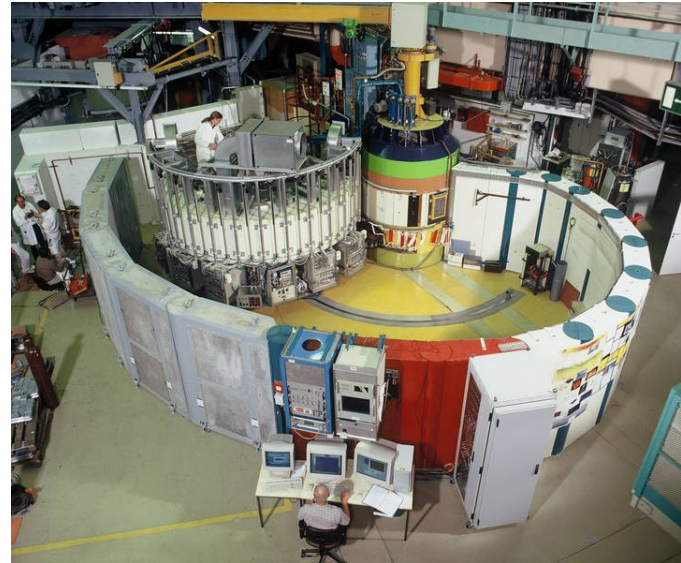
Powder  $\text{Na}_2\text{Ca}_3\text{Al}_2\text{F}_{14}$   $\phi=7\text{mm}$

V container

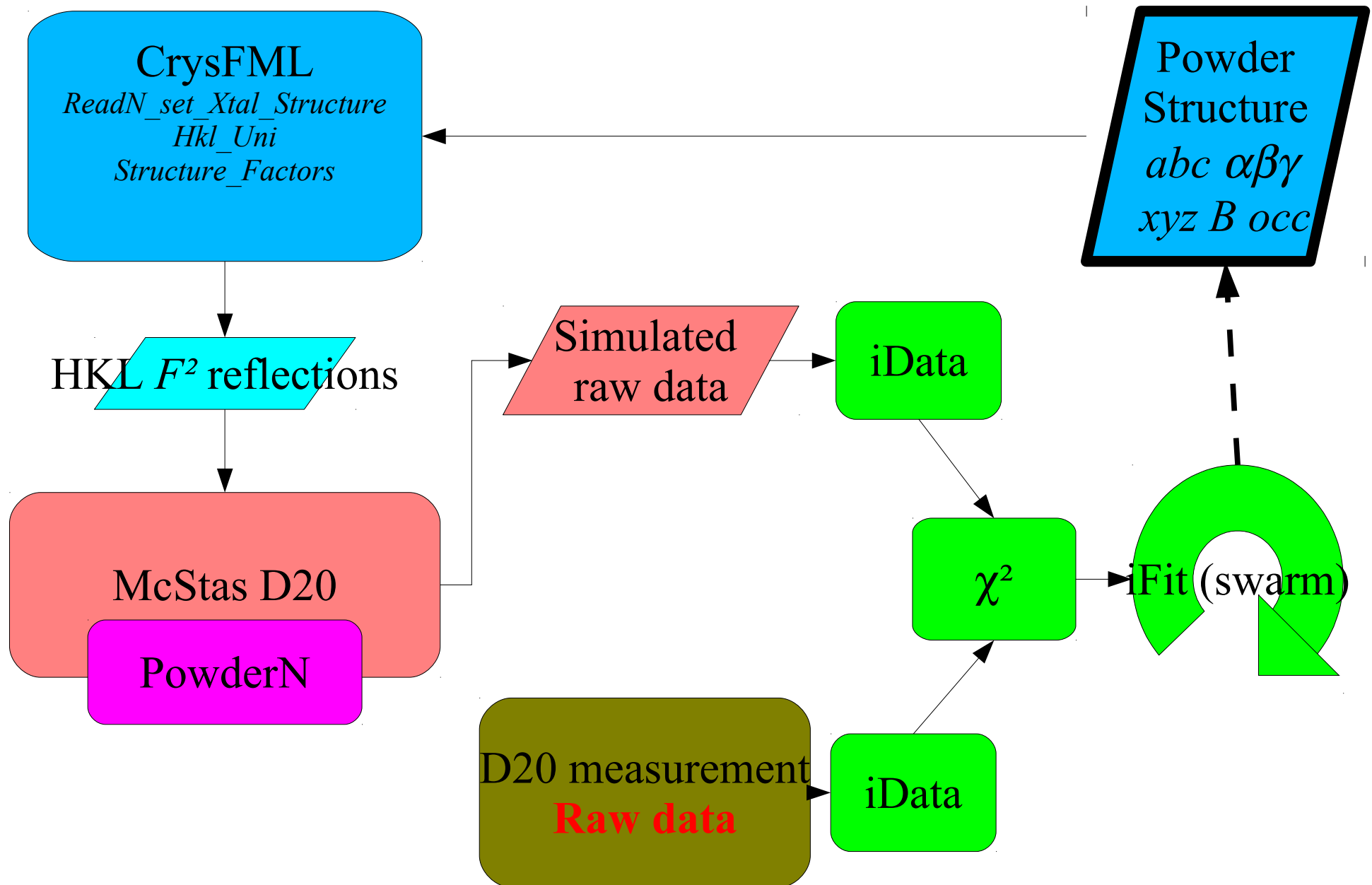
Detector:  $^3\text{He}$  microstrip  $5-150^\circ$

## Virtual experiment:

Built with *templateDIFF* from McStas 1.12c using the PowderN component.

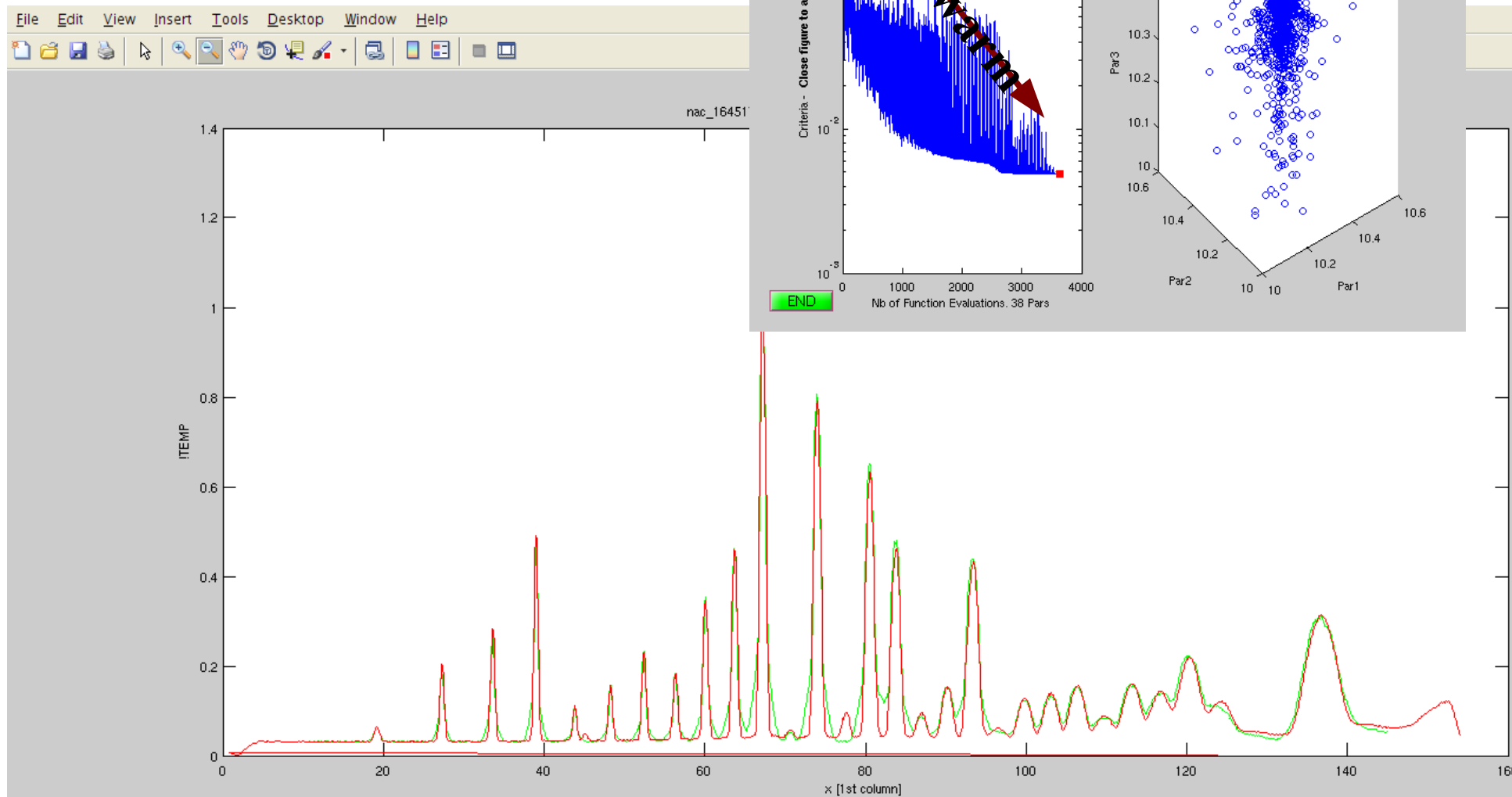


# Full simulation Rietveld



# Full simulation Rietveld : refinement

iFit displays the refinement steps in criteria value, *abc* values, and the two diffractograms (measured+simulated). Then we wait for convergence...





## Results and Lessons learned with the new Rietveld

### Results:

- ◆ The procedure is **fully functional** and automatic. Only requires the initial structure and the instrument model (which is given with *McStas*).
- ◆ The **only** added background is a constant, to model the reactor hall noise level.
- ◆ The final diffractogram fits the data (convergence achieved). Peaks shapes and background are well accounted for.
- ◆ Does not contain any 'trick', to fit asymmetry, background, non Gaussian/Voigt shapes, ...

### But:

- ◆ The refinement takes much longer than a legacy one (100x longer)
- ◆ The refinement is currently less satisfactory than the legacy one.

This new Rietveld methodology **will be greatly improved** in the next months (speed, accuracy), and may represent a usefull **complementary method** to e.g. FullProf and GSAS. Also, it may prove particularly efficient when peaks are **overlapping**, or when **background** level is difficult to fit, for instance with a mixed liquid+powder phases where we would use PowderN+Isotropic\_Sqw.

## Conclusion

### About iFit

- A lightweight, simple, intuitive yet efficient framework.
- Deployable as binary and Matlab source code
- Can link seamlessly to other software, e.g. Fullprof, McStas, ...
- Everything needed for data reduction and analysis, *any* dimensionality and data type.

### About “virtual experiment Rietveld”

- Very promising.
- Intrinsically includes instrument effects (resolution, environment, spurious, ...).
- Will be extended to Laue and SANS experiments.

<<http://ifit.mccode.org>>

E. Farhi et al, to appear in *J. Neut. Res.* **17** (2012).

<<http://www.mcstas.org>>

<<http://forge.ill.fr/projects/crysfml>>